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# Applications and Challenges in Computer Vision, Pattern Recognition, and Image Processing

Guest Editor:

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## **Message from the Guest Editor**

Dear Colleagues,

This Special Issue focuses on a wide range of applications in computer vision, pattern recognition, and image processing. We welcome submissions addressing practical issues in the real world and novel aspects in computer vision and image processing challenges.

Topics of interest for this Special Issue include but are not limited to:

- Object recognition;
- Segmentation;
- Image understanding;
- Object tracking and motion analysis;
- Face and pose;
- Low-level vision;
- Image enhancement;
- Video processing and analysis;
- Deep learning models in computer vision and image processing;
- Applications in vehicles, robotics, surveillance, medical images, and industrial inspection.

Dr. Yeong Jun Koh











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## **Message from the Editor-in-Chief**

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